

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/623,692	TAKEUCHI ET AL.	
Examiner		Art Unit	James Phan	
		2872	Page 1 of 1	

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	B	US-5,661,587	08-1997	Iwasaki, Takeo	359/205
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	US 2004/0036974 A1, Iizuka et al, 2/26/2004
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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